

Maximum Ratings, T_j=25°C unless otherwise specified

Ratings	Symbol		Units
Collector Emitter Voltage	V _{CES}	600	Volts
Gate Emitter Voltage	V _{GES}	±20	Volts
Collector Current	I _C	300	Amperes
Peak Collector Current	I _{CM}	600*	Amperes
Diode Forward Current	I _{FM}	300	Amperes
Diode Forward Surge Current	I _{FM}	600*	Amperes
Power Dissipation	P _d	1100	Watts
V Isolation	V _{RMS}	2500	Volts

Static Electrical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Units
Collector Cutoff Current	I _{CES}	V _{CE} =V _{CES}			1.0	mA
Gate Leakage Current	I _{GES}	V _{CE} =0V			0.5	μA
Gate-Emitter Threshold Voltage	V _{GE(th)}	I _C =30mA, V _{CE} =10V	4.5	6.0	7.5	Volts
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C =300A, V _{GE} =15V		2.1	2.8	Volts
	V _{CE(sat)}	I _C =300A, V _{GE} =15V, T _j =150°C		2.15		Volts
Total Gate Charge	Q _G	V _{CC} =300V, I _C =300A, V _{GS} =15V		900		nC
Diode Forward Voltage	V _{FM}	I _E =300A, V _{GS} =0V			2.8	Volts

Dynamic Electrical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Units
Input Capacitance	C _{ies}	V _{GE} =0V			30	nF
Output Capacitance	C _{oes}	V _{CE} =10V			10.5	nF
Reverse Transfer Capacitance	C _{res}	f=1MHz			6	nF
Turn on Delay time	t _{d(on)}	V _{CC} =300V			350	nS
Rise Time	t _r	I _C =300A			600	nS
Turn off delay time	t _{d(off)}	V _{GE1} =V _{GE2} =15V			350	nS
Fall Time	t _f	R _G =2.1Ω			300	nS
Diode Reverse Recovery Time	t _{rr}	I _E =300A			150	nS
Diode reverse Recovery Charge	Q _{rr}	di _E /dt=- 600A/μS		0.81		μC

Thermal and Mechanical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Units
Thermal Resistance, Junction to Case	R _{θJC}	Per IGBT			0.11	°C/W
Thermal Resistance, Junction to Case	R _{θJC}	Per Diode			0.24	°C/W



